

JCS740C-O-C-N-B-VB Datasheet

N-Channel 650 V (D-S) Super Junction Power MOSFET

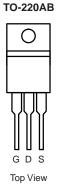
PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.42				
Q _g max. (nC)	38				
Q _{gs} (nC)	4				
Q _{gd} (nC)	4.2				
Configuration	Single				

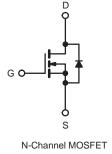
FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- · Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	650	N	
Gate-Source Voltage			V _{GS}	± 30	- V	
Constitutions Durain Comment (T. 150.80)	V _{GS} at 10 V	T _C = 25 °C	- I _D -	11	A	
Continuous Drain Current (T _J = 150 °C)		T _C = 100 °C		9.7		
Pulsed Drain Current ^a			I _{DM}	55	1	
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	132	mJ	
Maximum Power Dissipation			PD	83/83/31	W	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to +150	°C			
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$			dV/dt -	50	V/ns	
Reverse Diode dV/dt ^d				3.1		
Soldering Recommendations (Peak Temperature) c	Temperature) ^c for 10 s			300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





DADAMETED	NGS	T)/2					118/27		
PARAMETER	SYMBOL	TYP.			MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-			60		°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.6							
SPECIFICATIONS (T _J = 25 °C, u	nless otherw	ise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNI		
Static		- <u>I</u>				ļ			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	650	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			I _D = 1 mA	-	0.65	-	V/°C	
Gate-Source Threshold Voltage (N)	V _{GS(th)}		= V _{GS} , I _D =		2	-	4	V	
			$V_{GS} = \pm 20$		-	-	± 100	nA	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 30$		-	-	± 1	μA	
		V _{DS} =	$V_{DS} = 650 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	1		
Zero Gate Voltage Drain Current	$V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ °C}$			-	-	10	μA		
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$ $I_D = 5 A$		-	0.42	-	Ω		
Forward Transconductance		V _{DS} = 30 V, I _D = 5 A		-	16	-	S		
Dynamic		-							
Input Capacitance	C _{iss}	$V_{GS} = 0 V, V_{DS} = 100 V, f = 1 MHz$		-	680	-	pF		
Output Capacitance	Coss			-	140	-			
Reverse Transfer Capacitance	C _{rss}			-	5	-			
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	– V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	63	-			
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	113	-			
Total Gate Charge	Qg	V _{GS} = 10 V I _D = 5 A, V _{DS} = 520 V		-	38	56	nC		
Gate-Source Charge	Q _{gs}			-	4	-			
Gate-Drain Charge	Q _{gd}				-	4.5	-	1	
Turn-On Delay Time	t _{d(on)}			-	13	25			
Rise Time	t _r	Voo	= 520 V, I _C	= 5 A	-	11	35	ns	
Turn-Off Delay Time	t _{d(off)}		= 10 V, R _g		-	81	90		
Fall Time	t _f			-	25	40			
Gate Input Resistance	Rg	f = 1	MHz, ope	n drain	-	3.5	-	Ω	
Drain-Source Body Diode Characteristic	s								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11			
Pulsed Diode Forward Current	I _{SM}			-	-	55	A		
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 5 A, V _{GS} = 0 V		-	-	1.5	V		
Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 5 \text{ A},$ dl/dt = 100 A/µs, V _R = 400 V		-	270	-	ns		
Reverse Recovery Charge	Q _{rr}			_	3.3	-	μΟ		
Reverse Recovery Current	I _{RRM}			_	30	_	μ0 A		

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

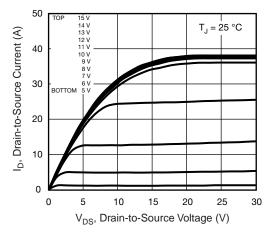


Fig. 1 - Typical Output Characteristics

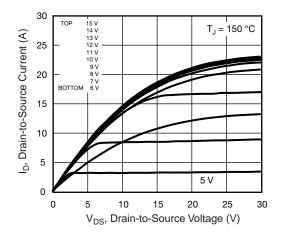


Fig. 2 - Typical Output Characteristics

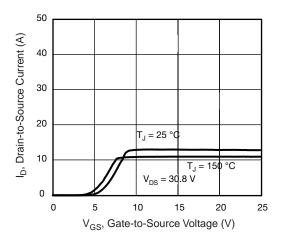


Fig. 3 - Typical Transfer Characteristics

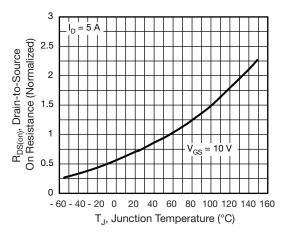


Fig. 4 - Normalized On-Resistance vs. Temperature

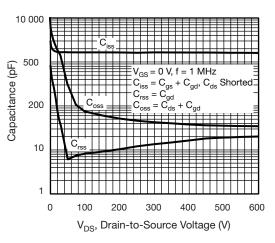


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

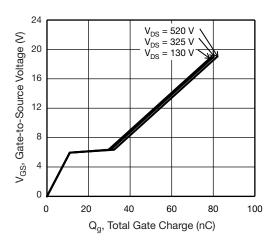


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



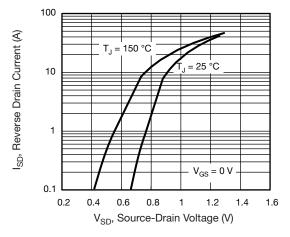
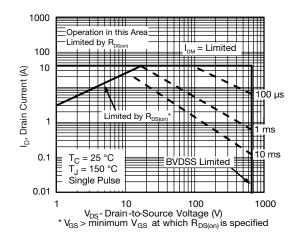


Fig. 7 - Typical Source-Drain Diode Forward Voltage





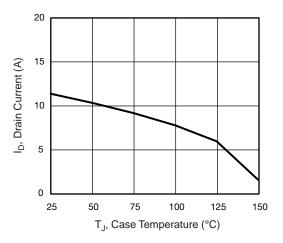


Fig. 9 - Maximum Drain Current vs. Case Temperature

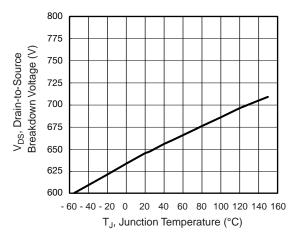


Fig. 10 - Temperature vs. Drain-to-Source Voltage

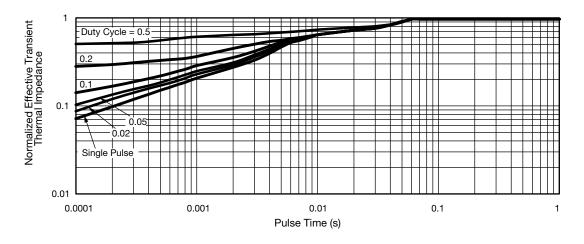


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



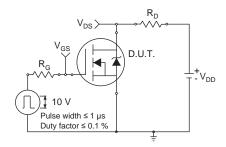


Fig. 12 - Switching Time Test Circuit

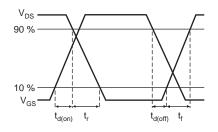


Fig. 13 - Switching Time Waveforms

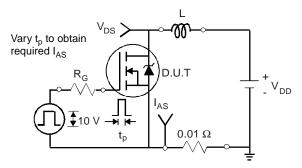


Fig. 14 - Unclamped Inductive Test Circuit

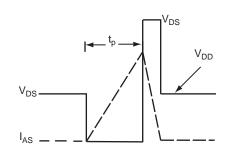


Fig. 15 - Unclamped Inductive Waveforms

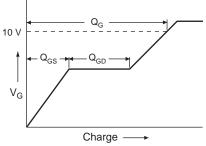


Fig. 16 - Basic Gate Charge Waveform

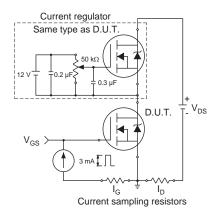
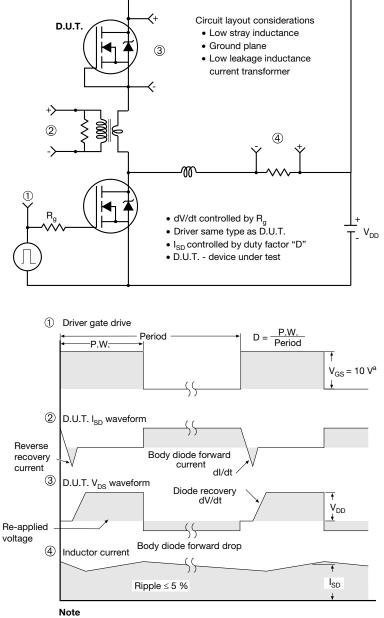


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

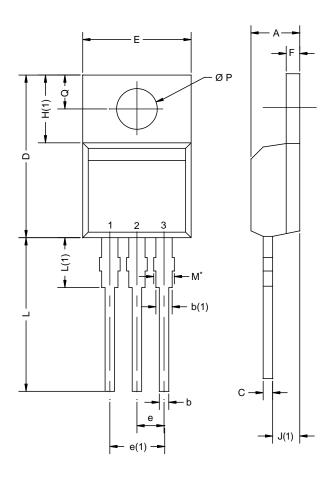


a. $V_{GS} = 5$ V for logic level devices

Fig. 18 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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